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210,2	6,228,694	5/8/01	Doyle e	t al.								
J.D.J.	6,406,973	6/18/02	Lee									
J.W.J.	6,281,532	8/28/01	Doyle e	et al.			·					
S.W.S.	5,683,934	11/4/97	Candel	aria								
2.22	6,368,931	4/9/02	Kubn	et al.								
I.W.L	5,310,446	5/10/94	Konish	i et al.	-							
2.22	4,853,076	8/1/89	Tsaur	et al.								
INL	2002/0090791	7/11/02	Doyle 6	et al.								
2.W.S	2002/0074598	6/20/02	Doyle o	et al.								
SN.Z.	6,509,618	1/21/03	Jan et	al.	_							
SW.L.	6,476,462	11/05/02	Shimiz	u et al.								
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ems.		6,362,082	3/26/02	Doyle et	t al.								
		6,228,694	5/8/01	Doyle e	raj.			 					
IWS.		5,565,697	10/15/96	Asakaw	/a et al.								
222		2003/0040158	2/27/03	Saitoh			_						
ews.		2002/0086472	7/4/02	Roberd	s et aL								
IN.Q.		6,521,964	2/18/03	Jan et a	d.								
24,2,		6,506,652	1/14/03	Jan et a	il.								
8.W.S.		5,081,513	1/14/92	Jackson	ı et al.								
VIII.		3,602,841	8/31/71	McGro	ddy								
		6,531,740	3/11/03	Bosco e	et al.								
221.2.		6,531,369	3/11/03	Ozkan	et al.								
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6,501,121	12/31/02	Yu et al						
(A), (A) 6,498,358	12/24/02	Lach et	al.					
6,493,497	12/10/02	Ramda	ni et al.	<u> </u>				
QNQ 6,403,975	6/11/02	Brunne	r et al.					
6,361,885	3/26/02	Chou						
(A) 6,255,169	7/3/01	Li et al.						
6,246,095	6/12/01	Brady 6	et al.					
6,165,383	12/26/00	Chou				·		
EAU, S. 6,133,071	10/17/00	Nagai						
8.N.A. 6,046,464	4/4/00	Schetzi	na		-			
(1), Q ₁ 6,025,280	2/15/00	Brady	et al.					
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£1.2.		5,880	0,040	3/9/99 .	Sun et a	٠.							
2, W.S.		5,86	1,651	1/19/99	Brasen	et al.							
S.W.S.		5,67	9,965	10/21/97	Schetzii	18							
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SNS.		5,56	1,302	10/1/96	Candela	aria							
S.W.S.		5,47	1,948	12/5/95	Burrou	ghes et al.							
S.W.S.		5,45	9,346	10/17/95	Asakaw	a et al.							
S.W.Z.		5,39	1,510	2/21/95	Hsu et a	ıL .							
21.J.Z.		5,37	1,399	12/6/94	Burrou	ghes et al.			·				
SWS.		5,10	8,843	4/28/92	Ohtaka	et al.							
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2118	4,958,213	9/18/90	Eklund	et al.			1		
2,1,8	4,665,415	5/12/97	Esaki et	al,			1		
S.N.S.	5,989,978	11/23/99	Peidous				-		
8128	6,284,626	9/4/01	Kim						
ew.e	6,274,444	8/14/01	Wang	· · · · · · · · · · · · · · · · · · ·					
8.W.S.	6,261,964	7/17/01	Wu et al.		-				
AUX.	6,221,735	4/24/01	Manley et	al.	-			,	
11.8	6,117,722	9/12/00	Wuu et al.	-	-				
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8.12.		6,060	5,545	5/23/00	Doshi et	al.							
IN.I.		6,008	3,126	12/28/99	Leedy								
211,2		5,940	5,559	8/31/99	Leedy			_					
JU.S.		5,840),593	11/24/98	Leedy								
J.N.J.		5,592	2,018	1/7/97	Leedy								
S.W.S.		5,592	2,007	1/7/97	Leedy								
SWL.		5,57	1,741 .	11/5/96	Leedy								
2W.S.		5,55	7,122	9/17/96	Shirvas	tava et al.							
LUL.		5,35	4,695	10/11/94	Leedy								
Silvid.		5,13	4,085	7/28/92	Gilgen	et al.							
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4,952,524 8/28/90 Lee et al.											
970 4,855,245 8/8/89 Neppl et al.											
2002/0086497 7/4/02 Kwok —											
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(1) 0 6,403,486 6/11/02 Lou —											
8.W.S. 6,284,623 9/4/01 Zhang et al.											
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999 2003/0057184 3/27/03 Yu et al. — —											
(1) 6,265,317 7/24/01 Chiu et al.											
2003/0067035 4/10/03 Tews et al.											
6,461,936 10/8/02 von Ehrenwall											
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J.W.S.	Kern Rim, et al., "Trans International Electron D Kern Rim, et al., "Chara	conductance	Enhand	cement in Deep Submi	cron Strain	ned-Si <i>n-</i> MOSF EDM 98, pp.	ETs", . 707 -710 ,			
&.N.S.	Symposium On VLSI T	echnology Di	aest of	Technical Papers, IEEI	E, pp 98-9	9, 2002,				
221.1.	Gregory Scott, et al., "N Induced Stress", Intern	VMOS Drive (ational Electr	Current on Devi	Reduction Caused by ces Meeting, 34.4.1, IE	Transistor EEE. Septe	Layout and Tre ember 1999, P	nch Isolation p. 827-8 <i>3</i> 0			
0112.	F. Ootsuka, et al., "A H	ighly Dense,	High-Pe	rformance 130nm nod	e CMOS	Technology for l	.arge Scale			
9110	System-on-a-Chip App Shinya Ito, et al., "Mecl	hanical Stress	s Effect	of Etch-Stop Nitride an	id its Impa	ct on Deep Sub	microh			
21,12	Transistor Design", Intel A. Shimizu, et al., "Local Enhancement", Internal	al Mechanica	I-Stress	Control (LMC): A New	Techniqu	e for CMOS-Pe	rformance			
and a	Enhancement", Interna K. Ota, et al., "Novel Lo Electron Devices Meeti	ocally Straine	d Chanr EE. Feb	nel Technique for high ruary 2002, pp. 2	Performan 7-30	ce 55nm CMOS	6", International			
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